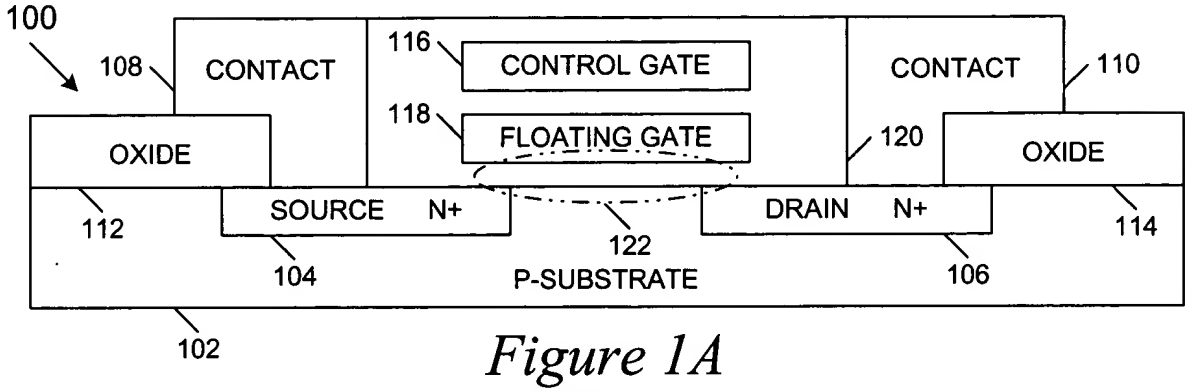


Figure 1A
(PRIOR ART)

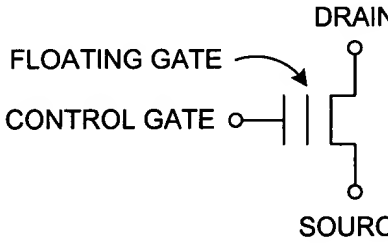


Figure 1B
(PRIOR ART)

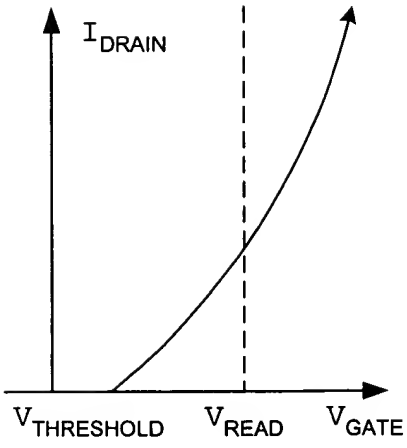


Figure 1C
(PRIOR ART)

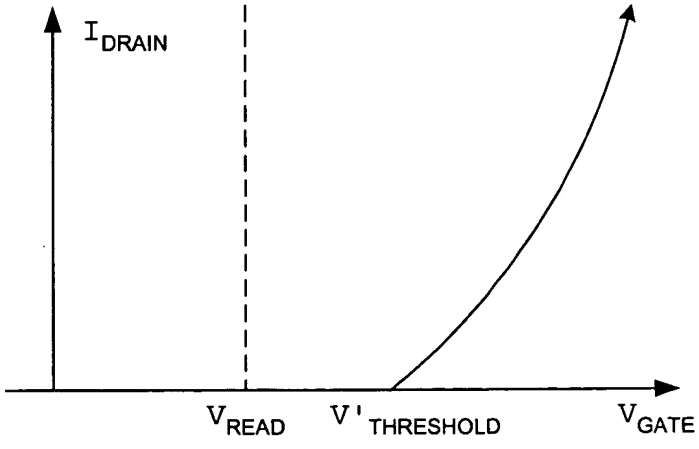


Figure 1D
(PRIOR ART)

CALCULATION OF NV MEMORY CELL RETENTION CHARACTERISTICS

q0, C	m0, kg	kb, J/K	h, J-s	hb, J-s
1.6022E-019	9.1095E-031	1.38062E-023	6.62617E-034	1.05459E-034

b0, eV (barrier)	ε1	mr, effective mass ratio	T, K degree
2.9	3.9	0.5	300

C	b
1.0630E-006	2.3854E+008

Seconds	Time Period
31536000	1 year
94608000	3 years
1.9E+008	6 years
2.8E+017	9 years
3.8E+008	12 years
4.7E+008	15 years
9.1E+009	18 years
6.6E+008	21 years
7.6E+008	24 years
8.5E+008	27 years
9.5E+008	30 years

Lfg um	0.6000	Channel length of floating gate device
Wfg um	1000.0000	Channel width of floating gate device.
Hfg um	0.0900	Thickness of floating gate polysilicon conductor
Wrx um	0.5000	Width of floating gate overlapping shallow trench isolation
Ttunox A	80	Tunnel oxide thickness
Tono A	190	Thickness of Oxide-Nitride-Oxide dielectric between floating gate and control gate for capacitive coupling
Tswox A	300	Thickness of sidewall oxide between floating gate and control gate for sidewall coupling
Xfd um	0.0500	Length of floating gate overlapping drain region of the floating gate MOSFET
Xfs um	0.3500	Length of floating gate overlapping source region of the floating gate MOSFET
Ainj um2	0.0438	Area of the electron tunneling region between the floating gate and the source for resetting the floating gate charge
Cfc fF	1089.5358	Capacitance between the floating gate and the control gate
Cfsx fF	0.4313	Capacitance between the floating gate and the silicon substrate
Cfd fF	0.1078	Capacitance between the floating gate and the drain
Cfs fF	0.7547	Capacitance between the floating gate and the source
Cfg fF	1090.8295	Total floating gate capacitance
Cr,wl	0.9988	Control gate to floating gate coupling ratio
Cr,src	0.0007	Source junction to floating gate coupling ratio
Vt,fg V	0.90	Threshold voltage of floating gate MOSFET
Verase	0.00	Erase voltage applied to the source(not used here, set to zero)
Vfg,ini	-5.00	Initial floating chaged voltage
Va	0.00	Actual erase volatge (equal to applied + charge stored on the floating)
S	3.76E+016	Derived parameter in the floating gate "erase" equation
X	1.27E+011	Derived parameter in the floating gate "erase" equation

Figure 1E
(PRIOR ART)

t, sec.	Vt,fg
0.00001	5.907
31536000	5.894
63072000	5.882
94608000	5.871
1.3E+008	5.861
1.6E+008	5.852
1.9E+008	5.843
2.2E+008	5.835
2.5E+008	5.827
2.8E+008	5.820
3.2E+008	5.814
3.5E+008	5.807
3.8E+008	5.801
4.1E+008	5.795
4.4E+008	5.790
4.7E+008	5.785
5E+008	5.780
5.4E+008	5.775
5.7E+008	5.770
6E+008	5.766
6.3E+008	5.762
6.6E+008	5.757
6.9E+008	5.753
7.3E+008	5.750
7.6E+008	5.746
7.9E+008	5.742
8.2E+008	5.739
8.5E+008	5.735
8.8E+008	5.732
9.1E+008	5.729
9.5E+008	5.726

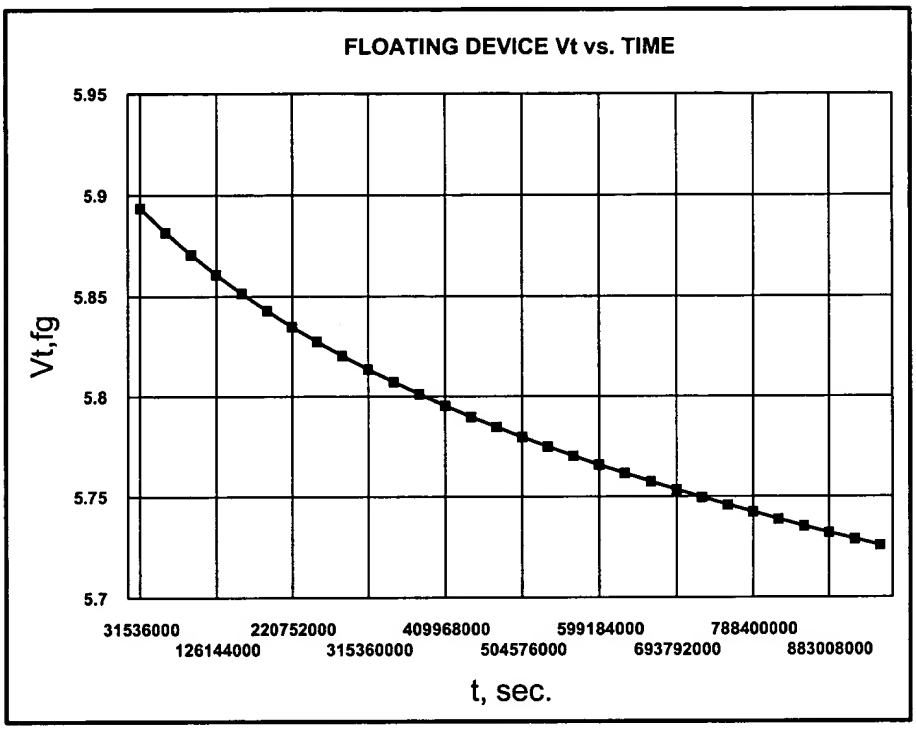


Figure 1F
(PRIOR ART)

CALCULATION OF NV MEMORY CELL RETENTION CHARACTERISTICS

q0, C	m0, kg	kb, J/K	h, J-s	hb, J-s
1.6022E-019	9.1095E-031	1.38062E-023	6.62617E-034	1.05459E-034

b0, eV (barrier)	ε1	mr, effective mass ratio	T, K degree
2.9	3.9	0.5	300

C	b
1.0630E-006	2.3854E+008

Seconds	Time Period
60	1 minute
3600	1 hour
86400	1 day
604800	1 week
2592000	1 month
31536000	1 year
1.3E+008	4 years
5E+008	16 years
1E+009	32 years

Lfg um	0.6000	Channel length of floating gate device
Wfg um	1000.0000	Channel width of floating gate device.
Hfg um	0.0900	Thickness of floating gate polysilicon conductor
Wrx um	0.5000	Width of floating gate overlapping shallow trench isolation
Ttunox A	80	Tunnel oxide thickness
Tono A	190	Thickness of Oxide-Nitride-Oxide dielectric between floating gate and control gate for capacitive coupling
Tswox A	300	Thickness of sidewall oxide between floating gate and control gate for sidewall coupling
Xfd um	0.0500	Length of floating gate overlapping drain region of the floating gate MOSFET
Xfs um	0.3500	Length of floating gate overlapping source region of the floating gate MOSFET
Ainj um2	0.0438	Area of the electron tunneling region between the floating gate and the source for resetting the floating gate charge
Cfc fF	1089.5358	Capacitance between the floating gate and the control gate
Cfsx fF	0.4313	Capacitance between the floating gate and the silicon substrate
Cfd fF	0.1078	Capacitance between the floating gate and the drain
Cfs fF	0.7547	Capacitance between the floating gate and the source
Cfg fF	1090.8295	Total floating gate capacitance
Cr,wl	0.9988	Control gate to floating gate coupling ratio
Cr,src	0.0007	Source junction to floating gate coupling ratio
Vt,fg V	0.90	Threshold voltage of floating gate MOSFET
Verase	0.00	Erase voltage applied to the source(not used here, set to zero)
Vfg,ini	-5.00	Initial floating chaged voltage
Va	0.00	Actual erase volatge (equal to applied + charge stored on the floating)
S	3.76E+016	Derived parameter in the floating gate "erase" equation
X	1.27E+011	Derived parameter in the floating gate "erase" equation

Figure 1G
(PRIOR ART)

t, sec.	Vt,fg
0.00001	5.907
2	5.907
4	5.907
8	5.907
16	5.907
32	5.907
64	5.907
128	5.907
256	5.907
512	5.907
1024	5.907
2048	5.907
4096	5.907
8192	5.907
16384	5.907
32768	5.907
65536	5.907
131072	5.907
262144	5.907
524288	5.907
1000000	5.907
2000000	5.906
4000000	5.905
8000000	5.904
16000000	5.900
32000000	5.894
64000000	5.881
1.3E+008	5.860
2.6E+008	5.827
5.1E+008	5.779
1E+009	5.718

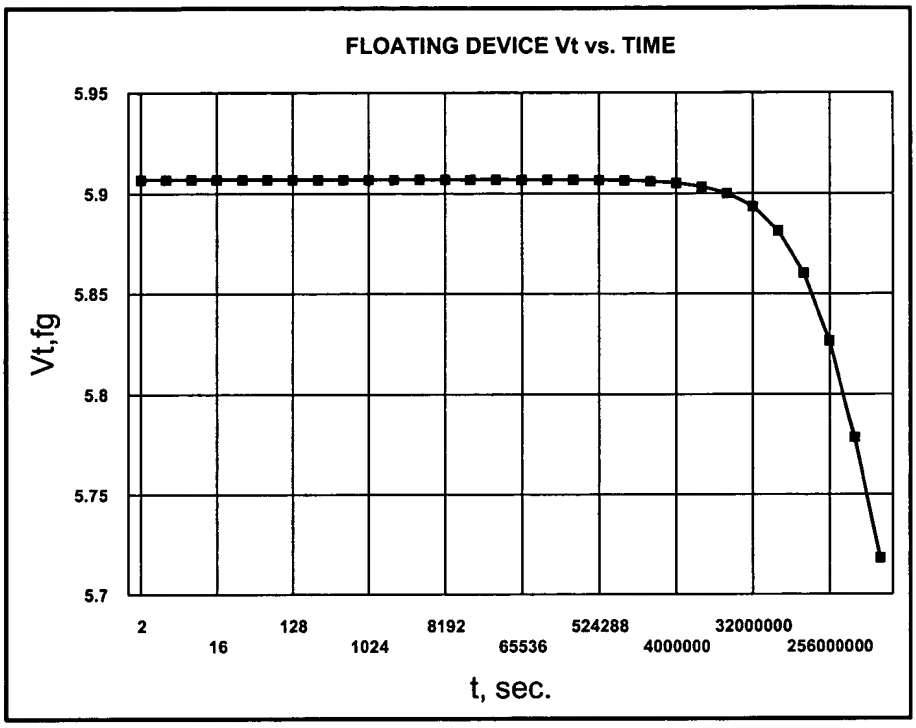


Figure 1H
(PRIOR ART)

CALCULATION OF NV MEMORY CELL RETENTION CHARACTERISTICS

q0, C	m0, kg	kb, J/K	h, J-s	hb, J-s
1.6022E-019	9.1095E-031	1.38062E-023	6.62617E-034	1.05459E-034

b0, eV (barrier)	ε1	mr, effective mass ratio	T, K degree
2.9	3.9	0.5	300

C	b
1.0630E-006	2.3854E+008

Seconds	Time Period
60	1 minute
3600	1 hour
86400	1 day
604800	1 week
2592000	1 month
31536000	1 year
1.3E+008	4 years
5E+008	16 years
1E+009	32 years

Lfg um	0.6000	Channel length of floating gate device
Wfg um	1000.0000	Channel width of floating gate device.
Hfg um	0.0900	Thickness of floating gate polysilicon conductor
Wrx um	0.5000	Width of floating gate overlapping shallow trench isolation
Ttunox A	85	Tunnel oxide thickness
Tono A	190	Thickness of Oxide-Nitride-Oxide dielectric between floating gate and control gate for capacitive coupling
Tswox A	300	Thickness of sidewall oxide between floating gate and control gate for sidewall coupling
Xfd um	0.0500	Length of floating gate overlapping drain region of the floating gate MOSFET
Xfs um	0.3500	Length of floating gate overlapping source region of the floating gate MOSFET
Ainj um2	0.0438	Area of the electron tunneling region between the floating gate and the source for resetting the floating gate charge
Cfc fF	1089.5358	Capacitance between the floating gate and the control gate
Cfsx fF	0.4059	Capacitance between the floating gate and the silicon substrate
Cfd fF	0.1015	Capacitance between the floating gate and the drain
Cfs fF	0.7103	Capacitance between the floating gate and the source
Cfg fF	1090.7534	Total floating gate capacitance
Cr,wl	0.9989	Control gate to floating gate coupling ratio
Cr,src	0.0007	Source junction to floating gate coupling ratio
Vt,fg V	0.90	Threshold voltage of floating gate MOSFET
Verase	0.00	Erase voltage applied to the source(not used here, set to zero)
Vfg,ini	-5.00	Initial floating chaged voltage
Va	0.00	Actual erase volatge (equal to applied + charge stored on the floating)
S	4.09E+017	Derived parameter in the floating gate "erase" equation
X	1.20E+011	Derived parameter in the floating gate "erase" equation

Figure 1I
(PRIOR ART)

t, sec.	Vt,fg
0.00001	5.907
2	5.907
4	5.907
8	5.907
16	5.907
32	5.907
64	5.907
128	5.907
256	5.907
512	5.907
1024	5.907
2048	5.907
4096	5.907
8192	5.907
16384	5.907
32768	5.907
65536	5.907
131072	5.907
262144	5.907
524288	5.907
1000000	5.907
2000000	5.907
4000000	5.906
8000000	5.906
16000000	5.906
32000000	5.905
64000000	5.904
1.3E+008	5.902
2.6E+008	5.898
5.1E+008	5.889
1E+009	5.874

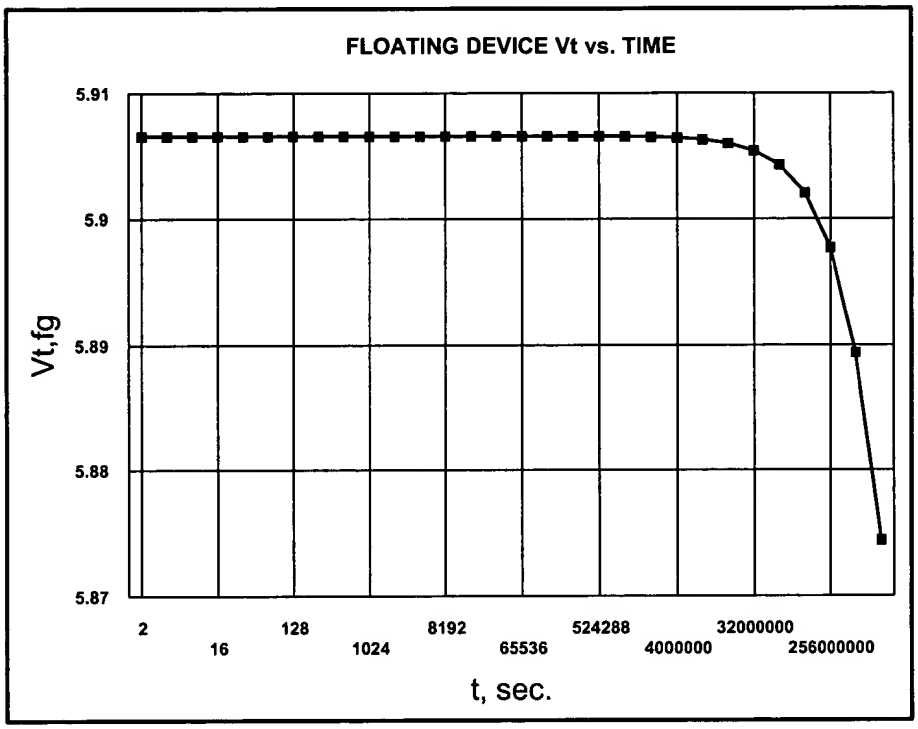


Figure 1J
(PRIOR ART)

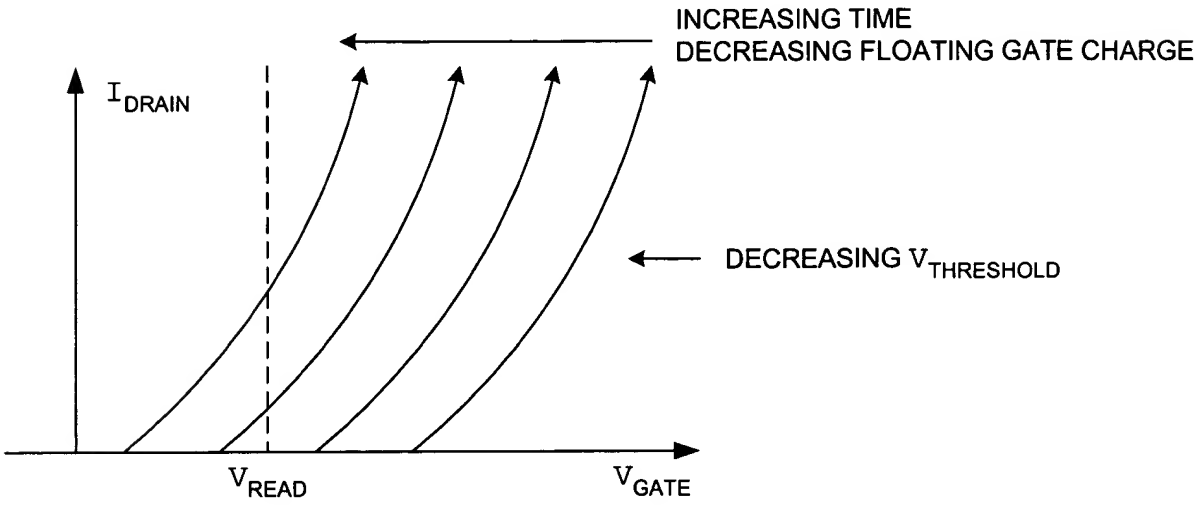

INCREASING TIME
DECREASING FLOATING GATE CHARGE
I_{DRAIN}
DECREASING $V_{THRESHOLD}$
V_{READ}
V_{GATE}

Figure 1K

CALCULATION OF NV MEMORY CELL RETENTION CHARACTERISTICS

q0, C	m0, kg	kb, J/K	h, J-s	hb, J-s
1.6022E-019	9.1095E-031	1.38062E-023	6.62617E-034	1.05459E-034

b0, eV (barrier)	ε1	mr, effective mass ratio	T, K degree
2.9	3.9	0.5	300

C	b
1.0630E-006	2.3854E+008

Seconds	Time Period
2592000	1 month
5184000	2 months
7776000	3 months
10368000	4 months
12960000	5 months
15552000	6 months
18144000	7 months
20736000	8 months
23328000	9 months
25920000	10 months
28512000	11 months
31104000	12 months
33696000	13 months
36288000	14 months
38880000	15 months
41472000	16 months

Lfg um	0.6000	Channel length of floating gate device
Wfg um	1000.0000	Channel width of floating gate device.
Hfg um	0.0900	Thickness of floating gate polysilicon conductor
Wrx um	0.5000	Width of floating gate overlapping shallow trench isolation
Ttunox A	65	Tunnel oxide thickness
Tono A	190	Thickness of Oxide-Nitride-Oxide dielectric between floating gate and control gate for capacitive coupling
Tswox A	300	Thickness of sidewall oxide between floating gate and control gate for sidewall coupling
Xfd um	0.0500	Length of floating gate overlapping drain region of the floating gate MOSFET
Xfs um	0.3500	Length of floating gate overlapping source region of the floating gate MOSFET
Ainj um2	0.0438	Area of the electron tunneling region between the floating gate and the source for resetting the floating gate charge
Cfc fF	1089.5358	Capacitance between the floating gate and the control gate
Cfsx fF	0.5308	Capacitance between the floating gate and the silicon substrate
Cfd fF	0.1327	Capacitance between the floating gate and the drain
Cfs fF	0.9288	Capacitance between the floating gate and the source
Cfg fF	1091.1281	Total floating gate capacitance
Cr,wl	0.9985	Control gate to floating gate coupling ratio
Cr,src	0.0009	Source junction to floating gate coupling ratio
Vt,fg V	0.90	Threshold voltage of floating gate MOSFET
Verase	0.00	Erase voltage applied to the source(not used here, set to zero)
Vfg,ini	-5.00	Initial floating chaged voltage
Va	0.00	Actual erase volatge (equal to applied + charge stored on the floating)
S	2.93E+013	Derived parameter in the floating gate "erase" equation
X	1.56E+011	Derived parameter in the floating gate "erase" equation

Figure 1L

t, sec.	Vt,fg
0.00001	5.909
1296000	5.596
2592000	5.508
3888000	5.456
5184000	5.420
6480000	5.392
7776000	5.369
9072000	5.349
10368000	5.333
11664000	5.318
12960000	5.305
14256000	5.293
15520000	5.283
16848000	5.273
18144000	5.264
19440000	5.256
20736000	5.248
22032000	5.240
23328000	5.234
24624000	5.227
25920000	5.221
27216000	5.215
28512000	5.210
29808000	5.204
31104000	5.199
32400000	5.195
33696000	5.190
34992000	5.185
36288000	5.181
37584000	5.177
38880000	5.173

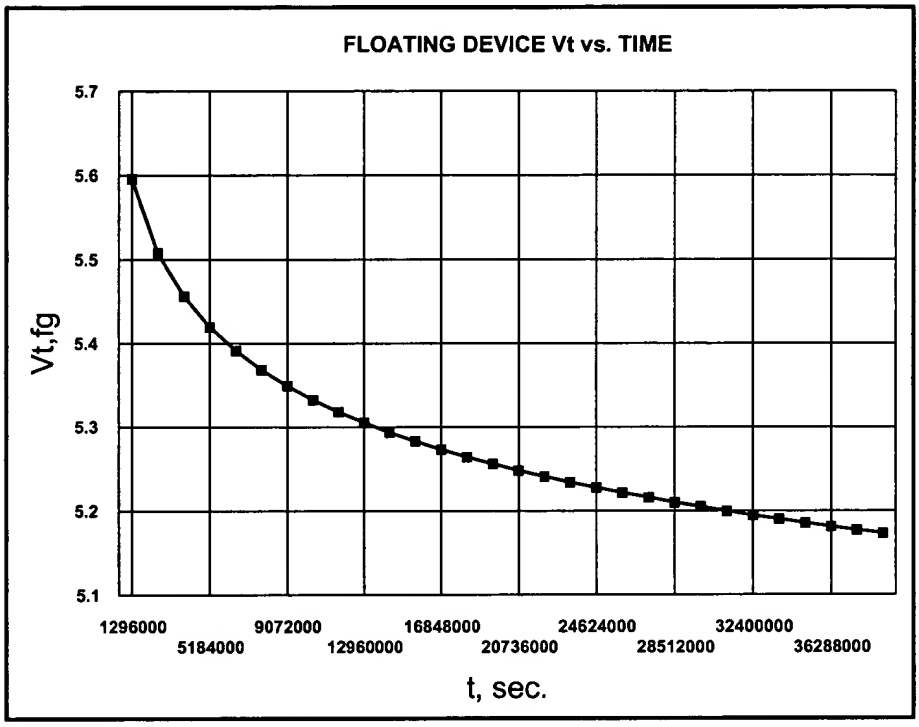


Figure 1M

CALCULATION OF NV MEMORY CELL RETENTION CHARACTERISTICS

q0, C	m0, kg	kb, J/K	h, J-s	hb, J-s
1.6022E-019	9.1095E-031	1.38062E-023	6.62617E-034	1.05459E-034

b0, eV (barrier)	ε1	mr, effective mass ratio	T, K degree
2.9	3.9	0.5	300

C	b
1.0630E-006	2.3854E+008

Seconds	Time Period
60	1 minute
3600	1 hour
86400	1 day
604800	1 week
1209600	2 weeks
2592000	1 month
5184000	2 months
10368000	4 months
15552000	6 months
20736000	8 months
25920000	10 months
31104000	12 months
36288000	14 months
41472000	16 months

Lfg um	0.6000	Channel length of floating gate device
Wfg um	1000.0000	Channel width of floating gate device.
Hfg um	0.0900	Thickness of floating gate polysilicon conductor
Wrx um	0.5000	Width of floating gate overlapping shallow trench isolation
Ttunox A	65	Tunnel oxide thickness
Tono A	190	Thickness of Oxide-Nitride-Oxide dielectric between floating gate and control gate for capacitive coupling
Tswox A	300	Thickness of sidewall oxide between floating gate and control gate for sidewall coupling
Xfd um	0.0500	Length of floating gate overlapping drain region of the floating gate MOSFET
Xfs um	0.3500	Length of floating gate overlapping source region of the floating gate MOSFET
Ainj um2	0.0438	Area of the electron tunneling region between the floating gate and the source for resetting the floating gate charge
Cfc fF	1089.5358	Capacitance between the floating gate and the control gate
Cfsx fF	0.5308	Capacitance between the floating gate and the silicon substrate
Cfd fF	0.1327	Capacitance between the floating gate and the drain
Cfs fF	0.9288	Capacitance between the floating gate and the source
Cfg fF	1091.1281	Total floating gate capacitance
Cr,wl	0.9985	Control gate to floating gate coupling ratio
Cr,src	0.0009	Source junction to floating gate coupling ratio
Vt,fg V	0.90	Threshold voltage of floating gate MOSFET
Verase	0.00	Erase voltage applied to the source(not used here, set to zero)
Vfg,ini	-5.00	Initial floating chaged voltage
Va	0.00	Actual erase volatge (equal to applied + charge stored on the floating)
S	2.93E+013	Derived parameter in the floating gate "erase" equation
X	1.56E+011	Derived parameter in the floating gate "erase" equation

Figure 1N

t, sec.	Vt,fg
0.00001	5.909
2	5.909
4	5.909
8	5.909
16	5.909
32	5.909
64	5.909
128	5.909
256	5.908
512	5.908
1024	5.908
2048	5.907
4096	5.905
8192	5.902
16384	5.895
32768	5.883
65536	5.861
131072	5.824
262144	5.771
524288	5.702
604800	5.686
1209600	5.604
2592000	5.508
5184000	5.420
10368000	5.333
15552000	5.283
20736000	5.248
25920000	5.221
31104000	5.199
36288000	5.181
41472000	5.166

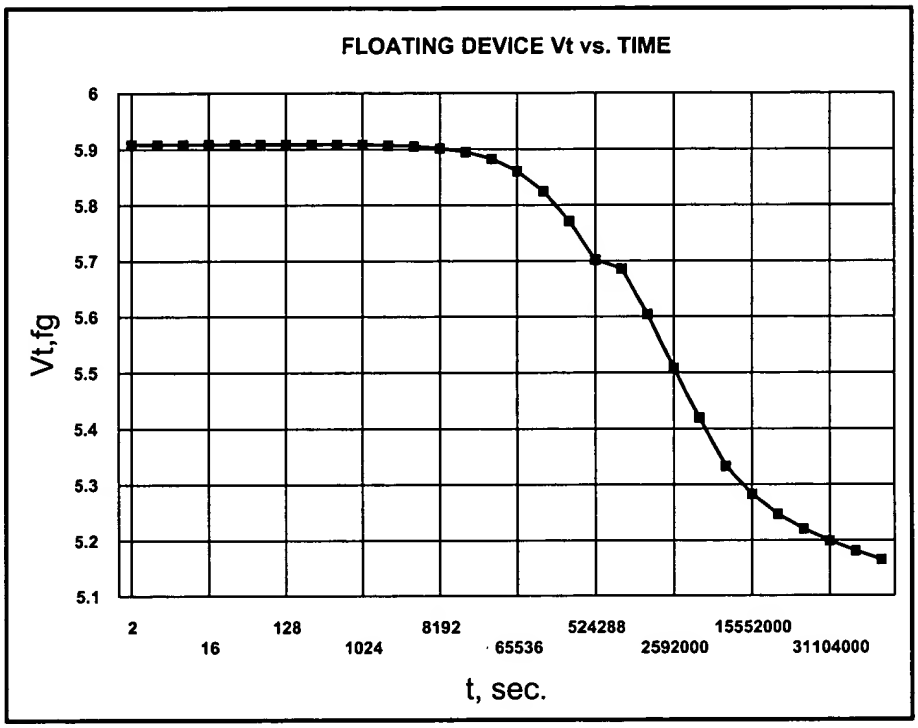


Figure 10

CALCULATION OF NV MEMORY CELL RETENTION CHARACTERISTICS

q0, C	m0, kg	kb, J/K	h, J-s	hb, J-s
1.6022E-019	9.1095E-031	1.38062E-023	6.62617E-034	1.05459E-034

b0, eV (barrier)	εl	mr, effective mass ratio	T, K degree
2.9	3.9	0.5	300

C	b
1.0630E-006	2.3854E+008

Seconds	Time Period
60	1 minute
3600	1 hour
86400	1 day
604800	1 week
1209600	2 weeks
2592000	1 month
5184000	2 months
10368000	4 months
15552000	6 months
20736000	8 months
25920000	10 months
31104000	12 months
36288000	14 months
41472000	16 months

Lfg um	0.6000	Channel length of floating gate device
Wfg um	1000.0000	Channel width of floating gate device.
Hfg um	0.0900	Thickness of floating gate polysilicon conductor
Wrx um	0.5000	Width of floating gate overlapping shallow trench isolation
Ttunox A	60	Tunnel oxide thickness
Tono A	190	Thickness of Oxide-Nitride-Oxide dielectric between floating gate and control gate for capacitive coupling
Tswox A	300	Thickness of sidewall oxide between floating gate and control gate for sidewall coupling
Xfd um	0.0500	Length of floating gate overlapping drain region of the floating gate MOSFET
Xfs um	0.3500	Length of floating gate overlapping source region of the floating gate MOSFET
Ainj um2	0.0438	Area of the electron tunneling region between the floating gate and the source for resetting the floating gate charge
Cfc fF	1089.5358	Capacitance between the floating gate and the control gate
Cfsx fF	0.5750	Capacitance between the floating gate and the silicon substrate
Cfd fF	0.1438	Capacitance between the floating gate and the drain
Cfs fF	1.0063	Capacitance between the floating gate and the source
Cfg fF	1091.2608	Total floating gate capacitance
Cr,wl	0.9984	Control gate to floating gate coupling ratio
Cr,src	0.0009	Source junction to floating gate coupling ratio
Vt,fg V	0.90	Threshold voltage of floating gate MOSFET
Verase	0.00	Erase voltage applied to the source(not used here, set to zero)
Vfg,ini	-5.00	Initial floating chaged voltage
Va	0.00	Actual erase volatge (equal to applied + charge stored on the floating)
S	2.70E+012	Derived parameter in the floating gate "erase" equation
X	1.69E+011	Derived parameter in the floating gate "erase" equation

Figure 1P

t, sec.	Vt,fg
0.00001	5.909
2	5.909
4	5.909
8	5.909
16	5.909
32	5.909
64	5.909
128	5.908
256	5.907
512	5.904
1024	5.898
2048	5.888
4096	5.870
8192	5.838
16384	5.789
32768	5.721
65536	5.639
131072	5.549
262144	5.455
524288	5.360
604800	5.341
1209600	5.250
2592000	5.152
5184000	5.067
10368000	4.985
15552000	4.938
20736000	4.906
25920000	4.881
31104000	4.861
36288000	4.844
41472000	4.830

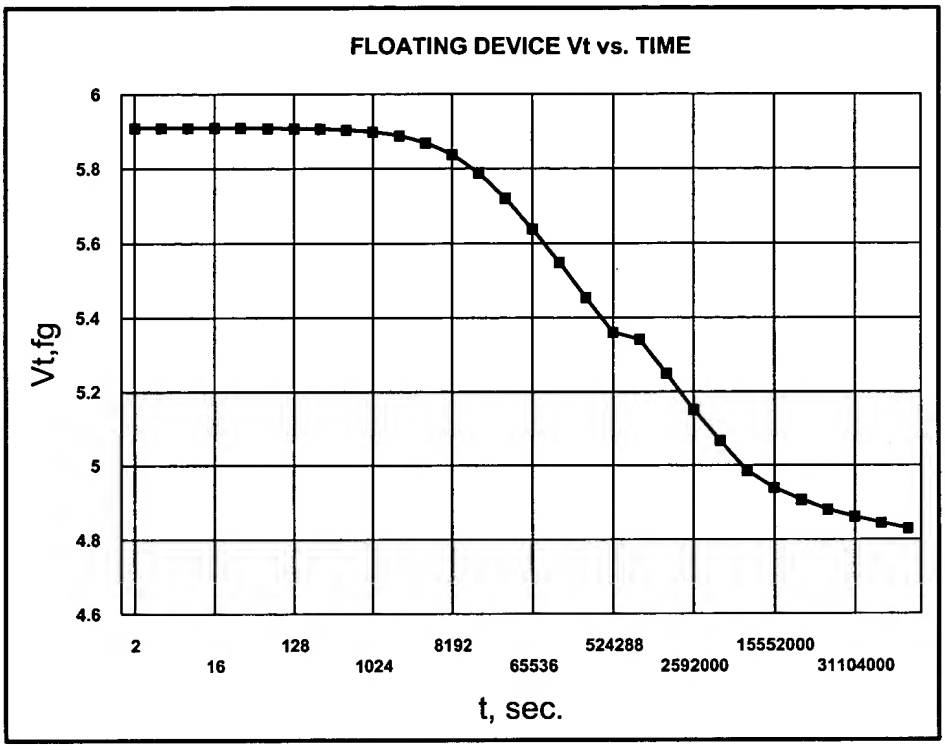


Figure 1Q

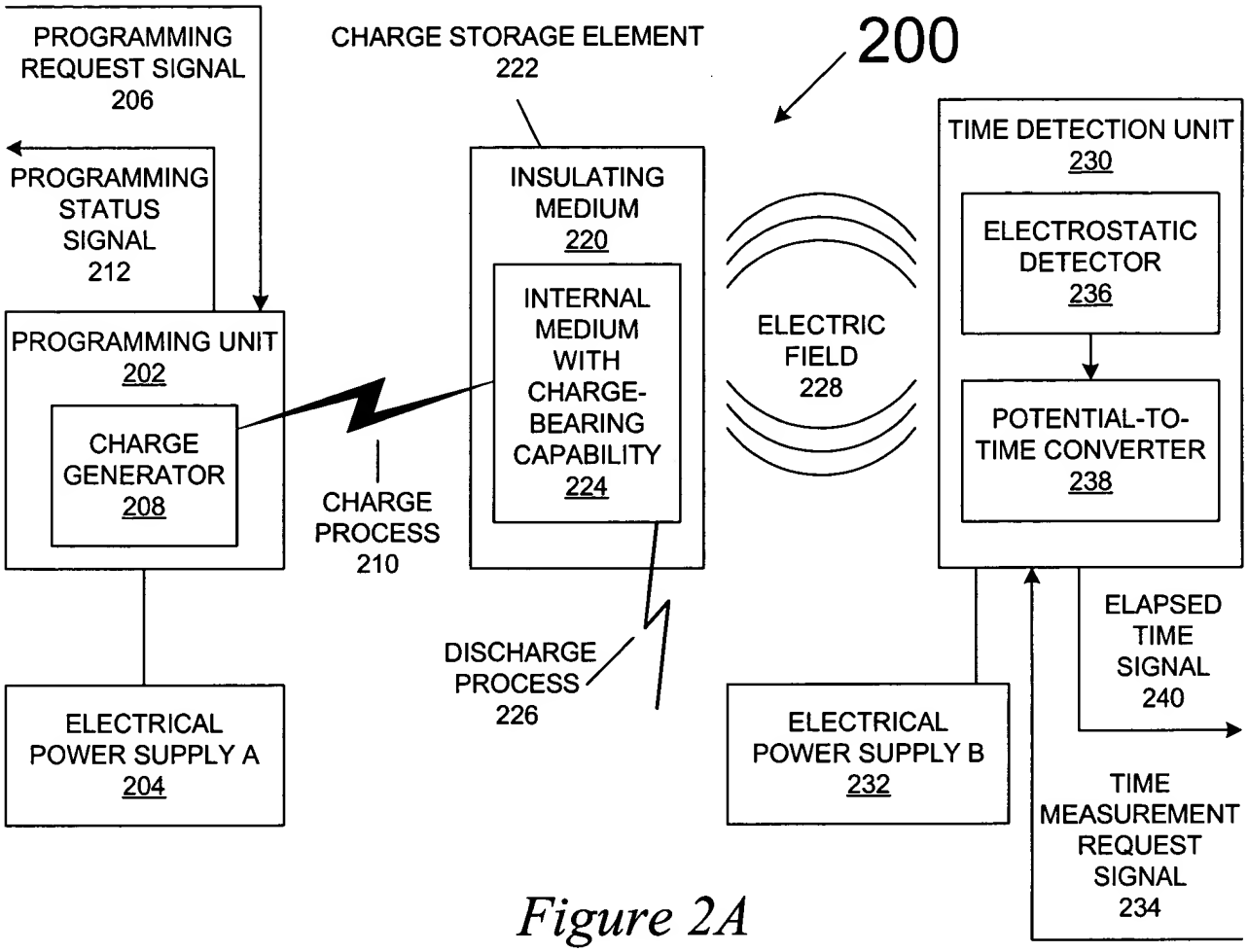


Figure 2A

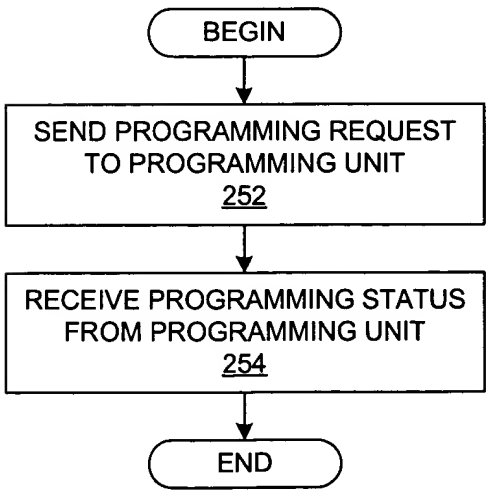


Figure 2B

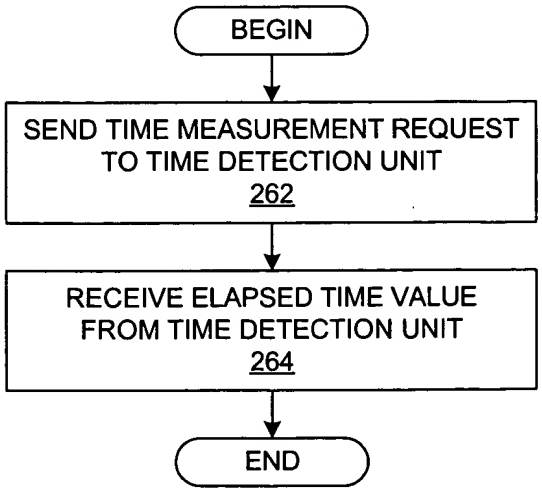
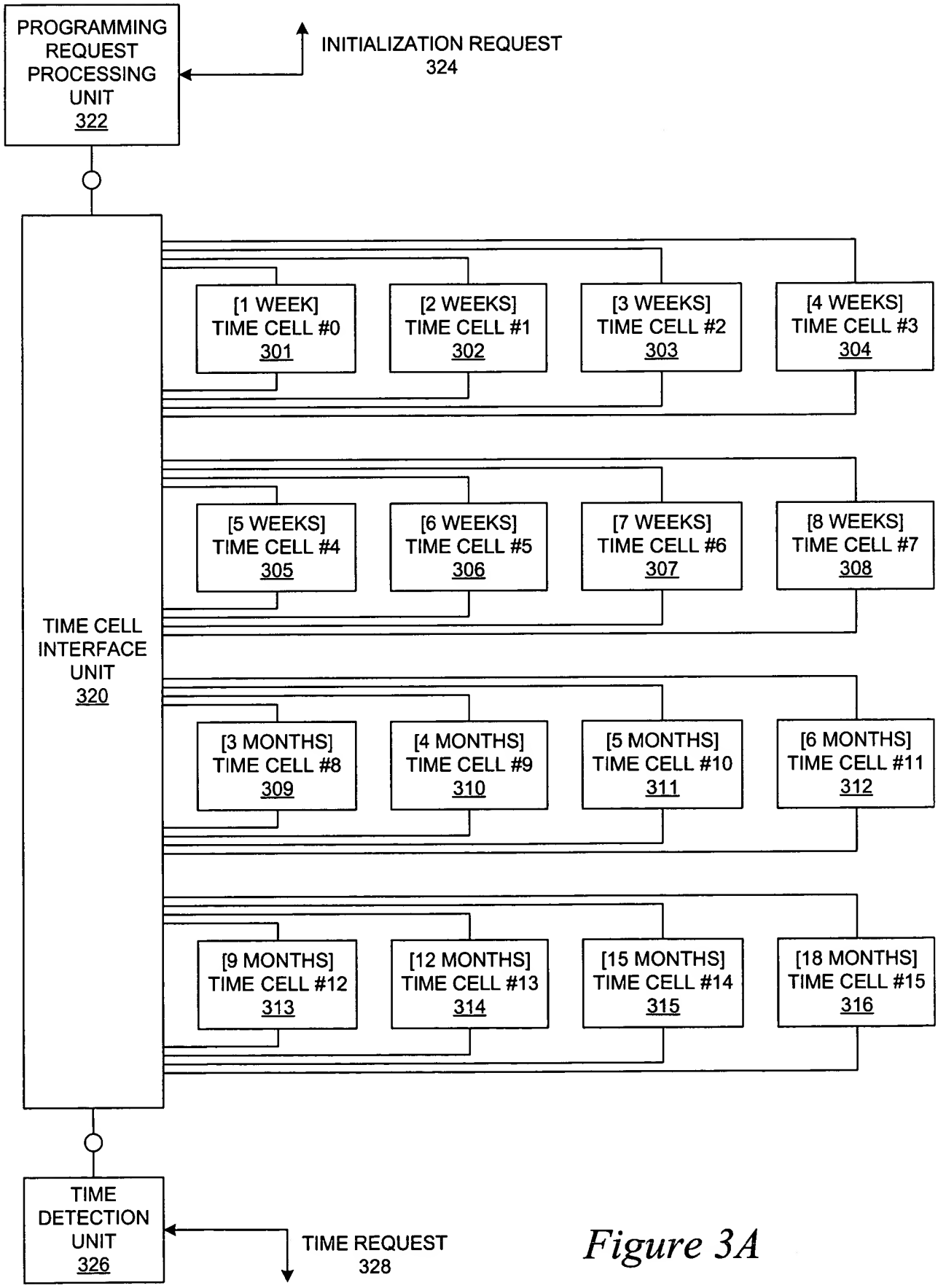


Figure 2C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INITIALIZATION REQUEST 324
TIME CELL INTERFACE UNIT 320
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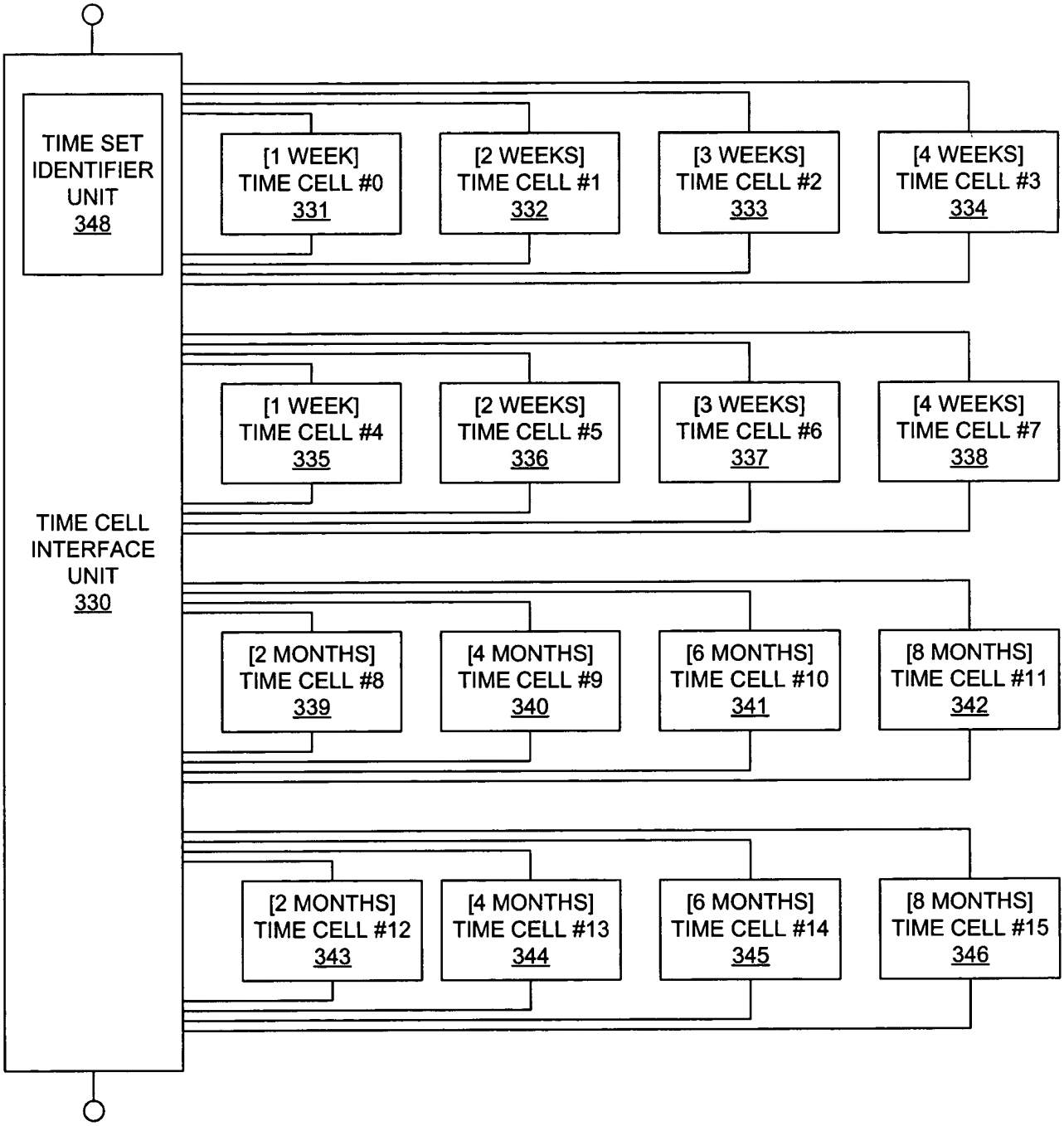
[3 WEEKS] TIME CELL #2 303
[4 WEEKS] TIME CELL #3 304
[5 WEEKS] TIME CELL #4 305
[6 WEEKS] TIME CELL #5 306
[7 WEEKS] TIME CELL #6 307
[8 WEEKS] TIME CELL #7 308
[3 MONTHS] TIME CELL #8 309
[4 MONTHS] TIME CELL #9 310
[5 MONTHS] TIME CELL #10 311
[6 MONTHS] TIME CELL #11 312
[9 MONTHS] TIME CELL #12 313
[12 MONTHS] TIME CELL #13 314
[15 MONTHS] TIME CELL #14 315
[18 MONTHS] TIME CELL #15 316
TIME DETECTION UNIT 326
TIME REQUEST 328

Figure 3A


TIME SET IDENTIFIER UNIT 348
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[1 WEEK] TIME CELL #4 335
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[3 WEEKS] TIME CELL #6 337
[4 WEEKS] TIME CELL #7 338
[2 MONTHS] TIME CELL #8 339
[4 MONTHS] TIME CELL #9 340
[6 MONTHS] TIME CELL #10 341
[8 MONTHS] TIME CELL #11 342
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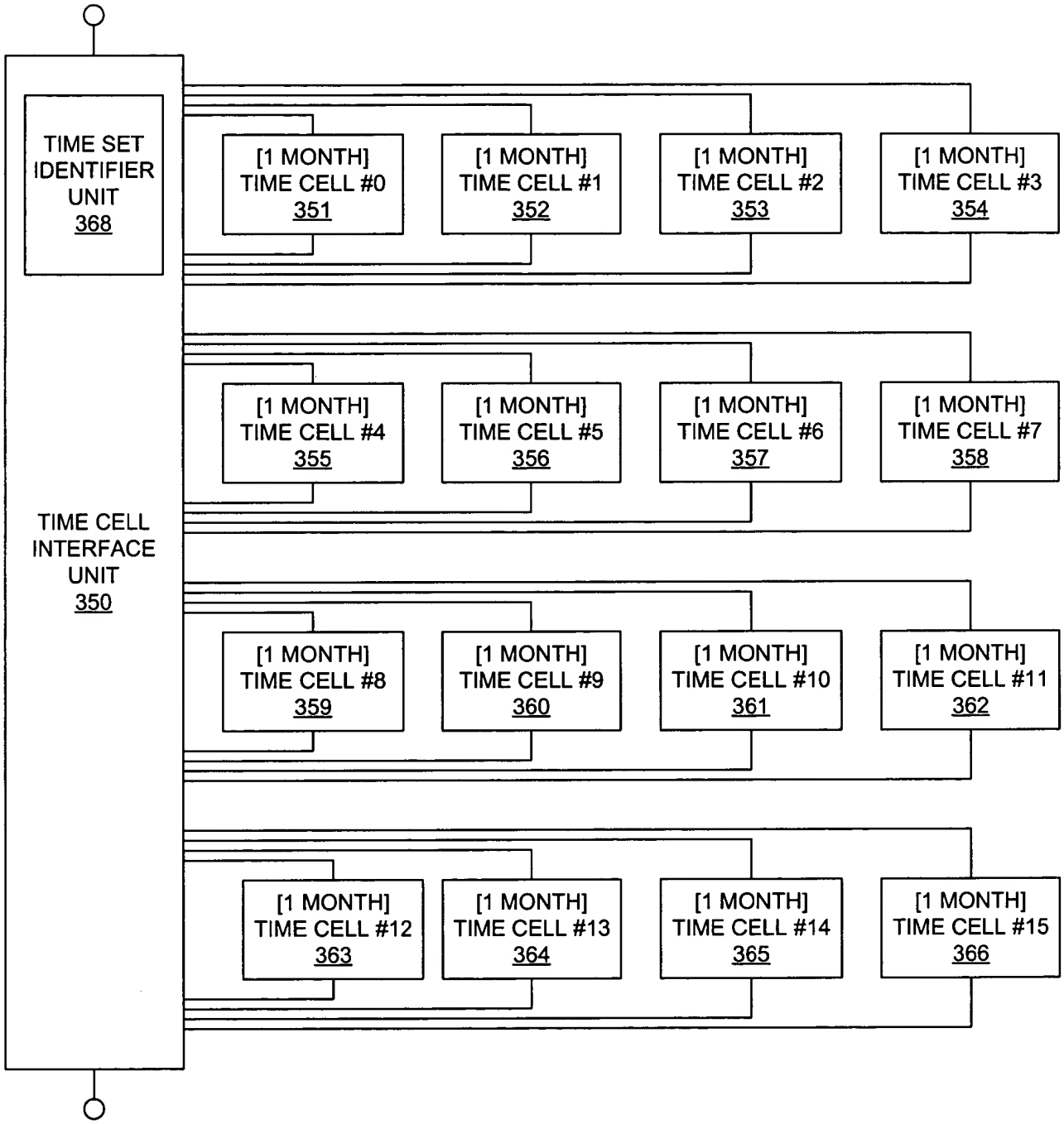
[6 MONTHS] TIME CELL #14 345
[8 MONTHS] TIME CELL #15 346

Figure 3B


TIME SET IDENTIFIER UNIT 368
TIME CELL INTERFACE UNIT 350
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[1 MONTH] TIME CELL #15 366

Figure 3C

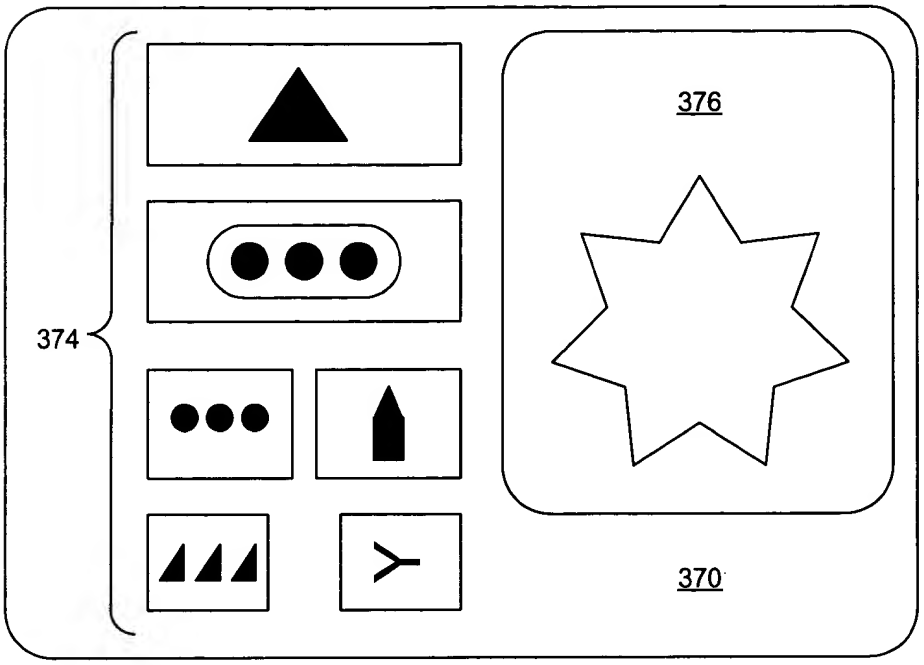


Figure 3D

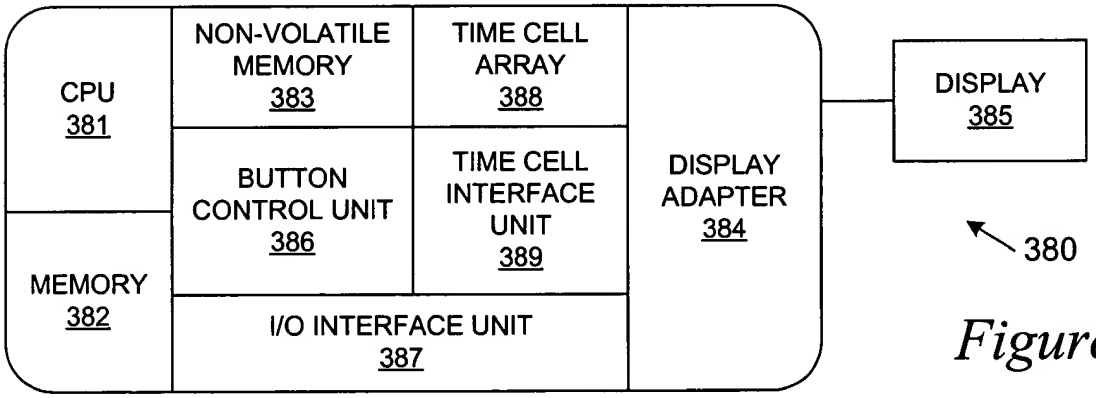


Figure 3E

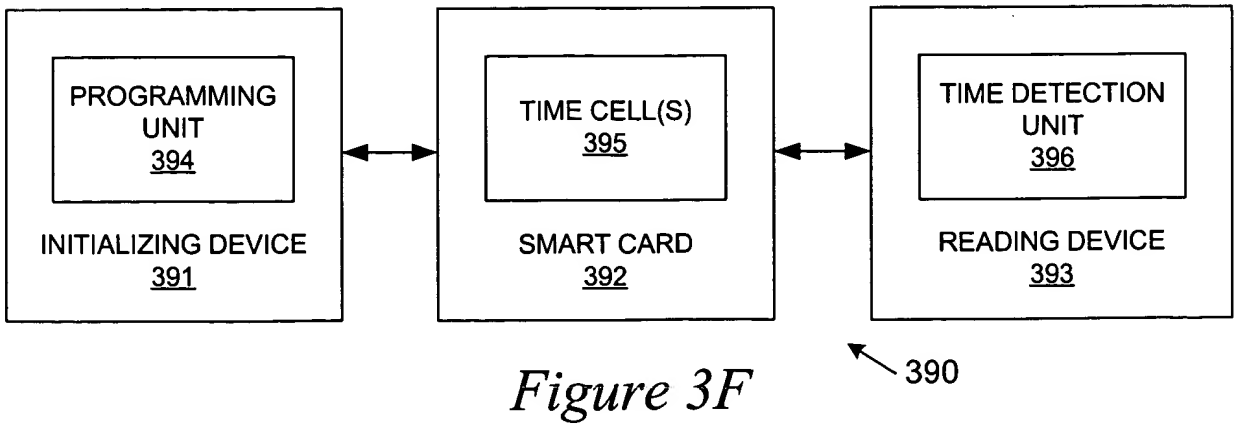


Figure 3F

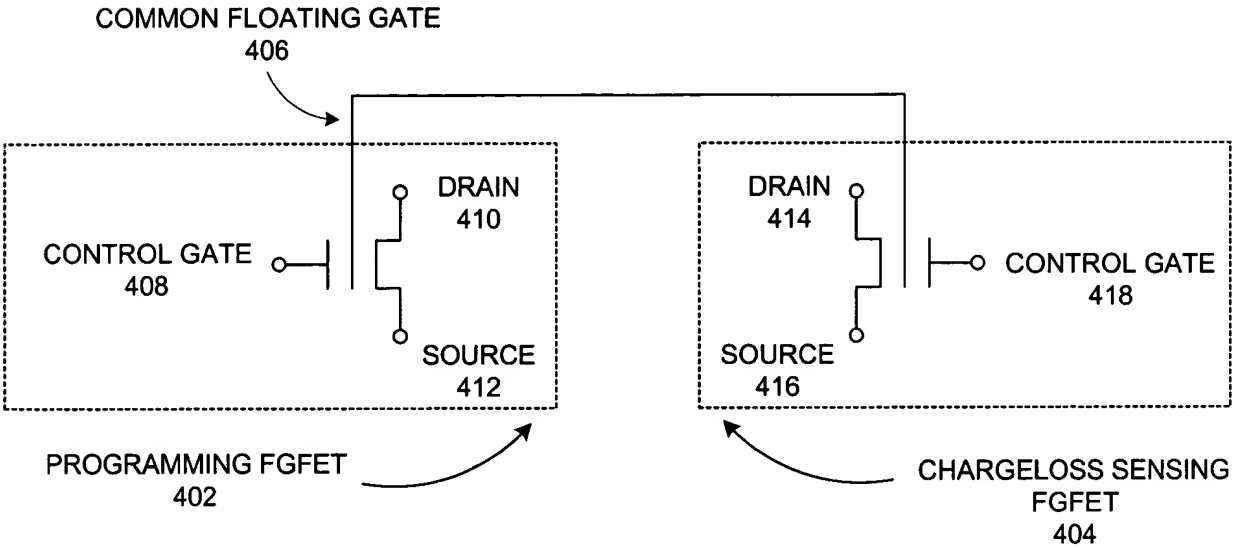


Figure 4A

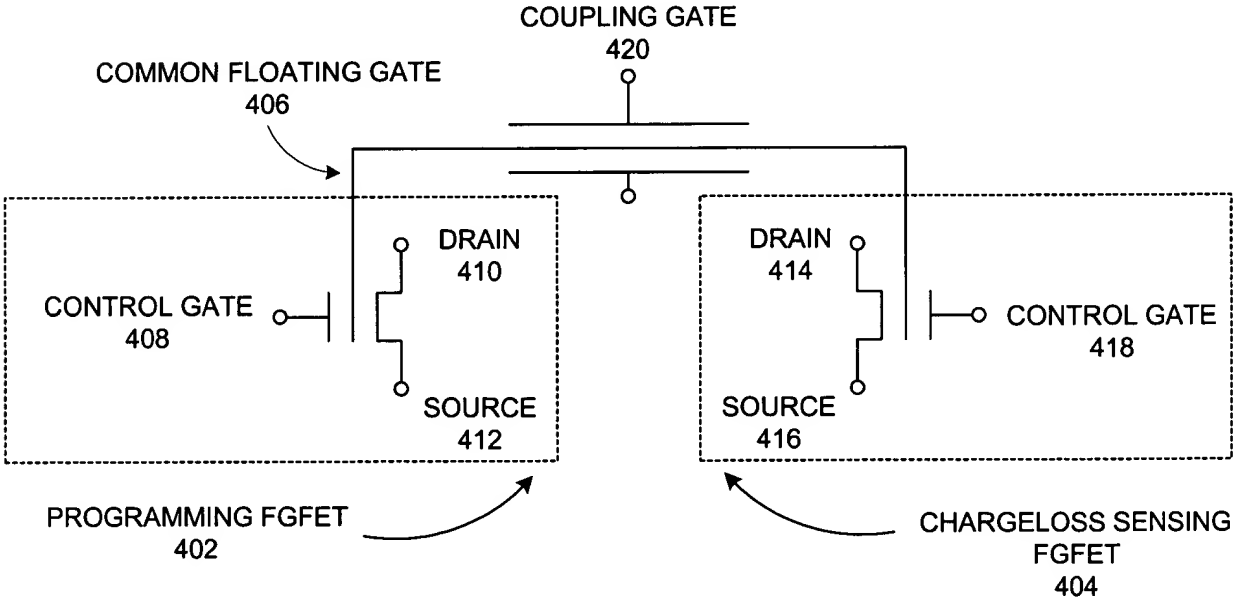
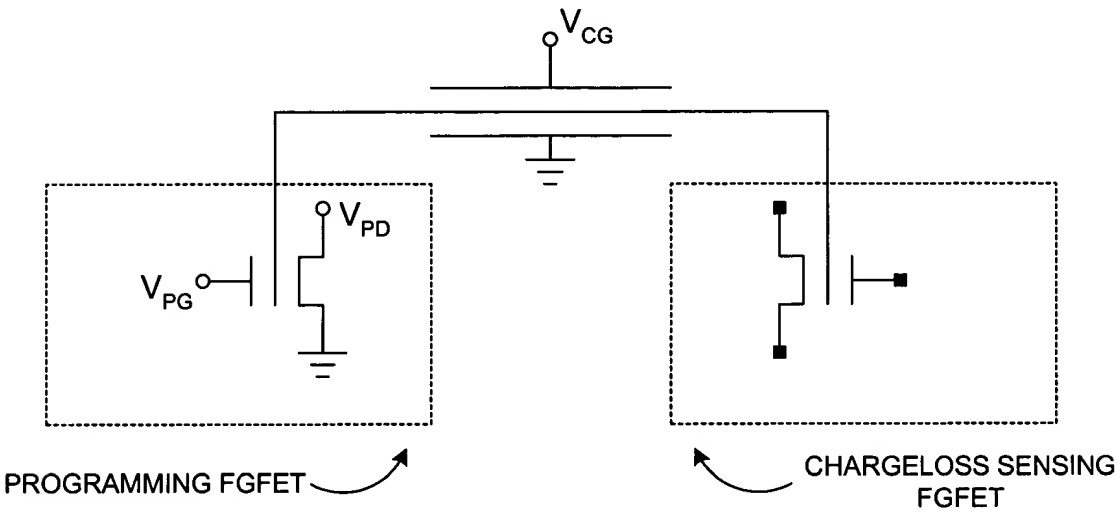
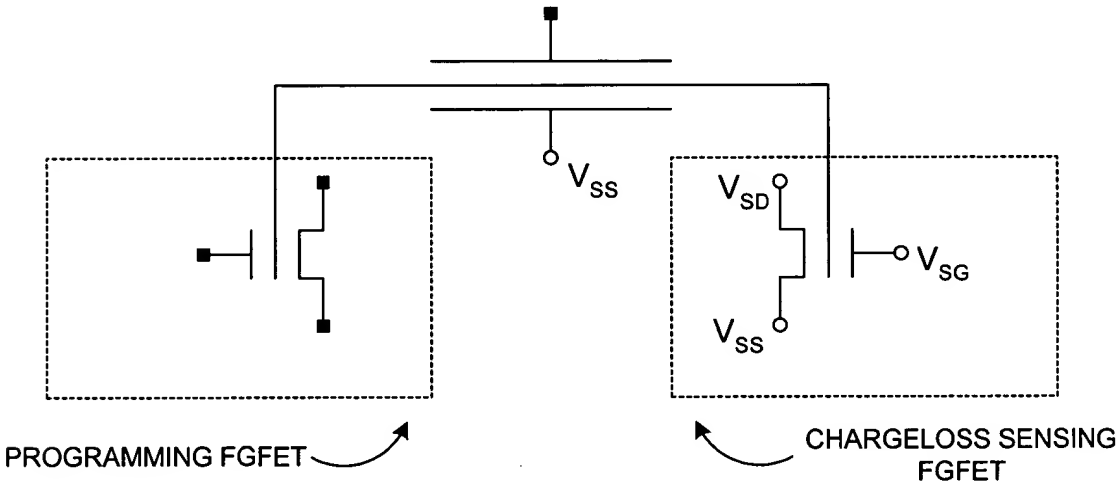


Figure 4B



VOLTAGES DURING PROGRAMMING OPERATION

Figure 4C



VOLTAGES DURING SENSING OPERATION

Figure 4D

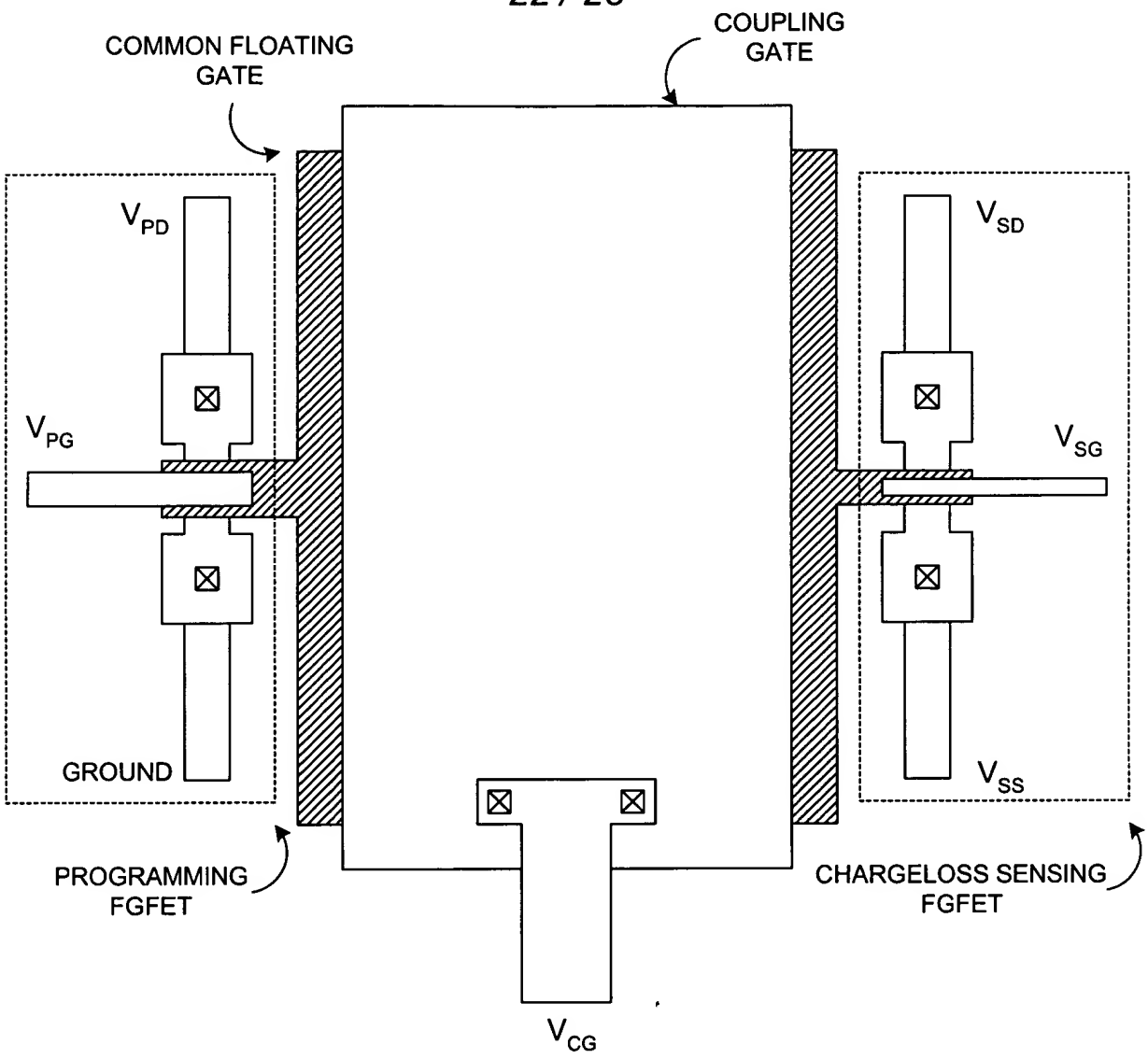


Figure 4E

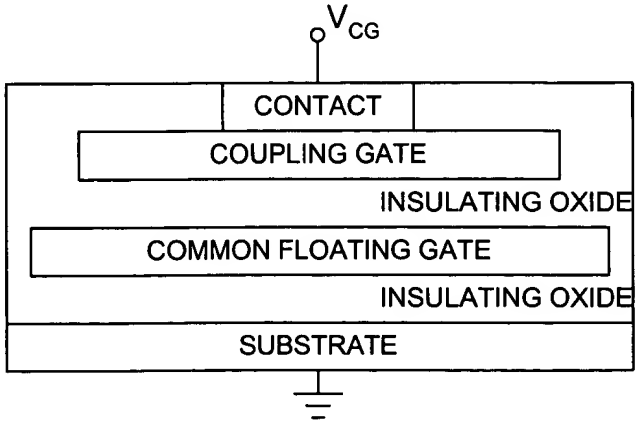


Figure 4F

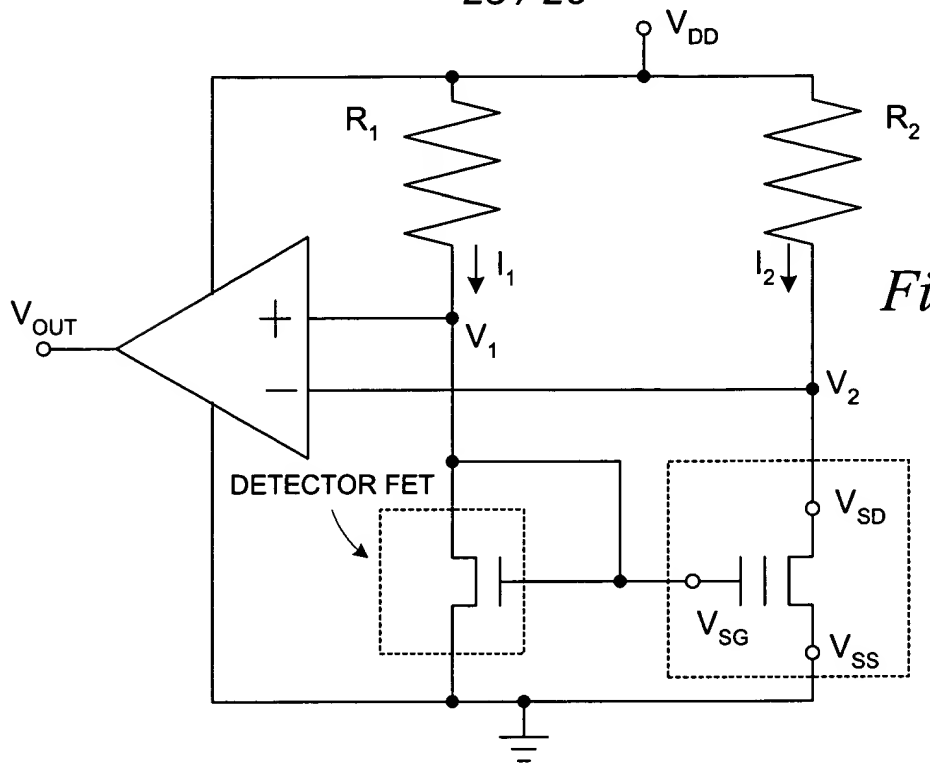


Figure 4G

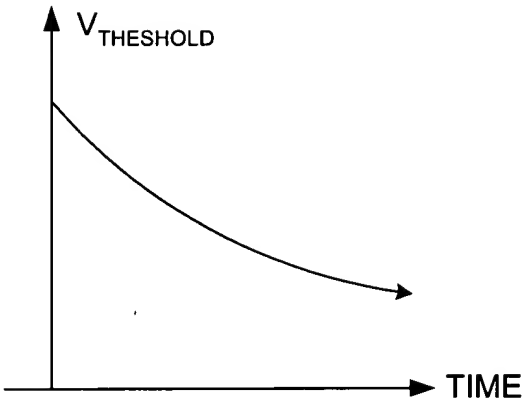


Figure 4H

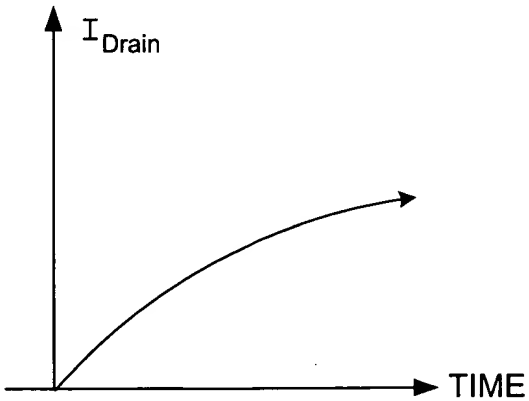


Figure 4I

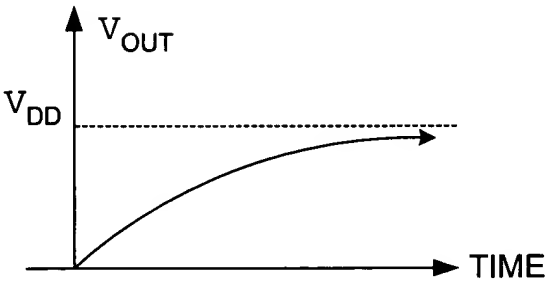


Figure 4J

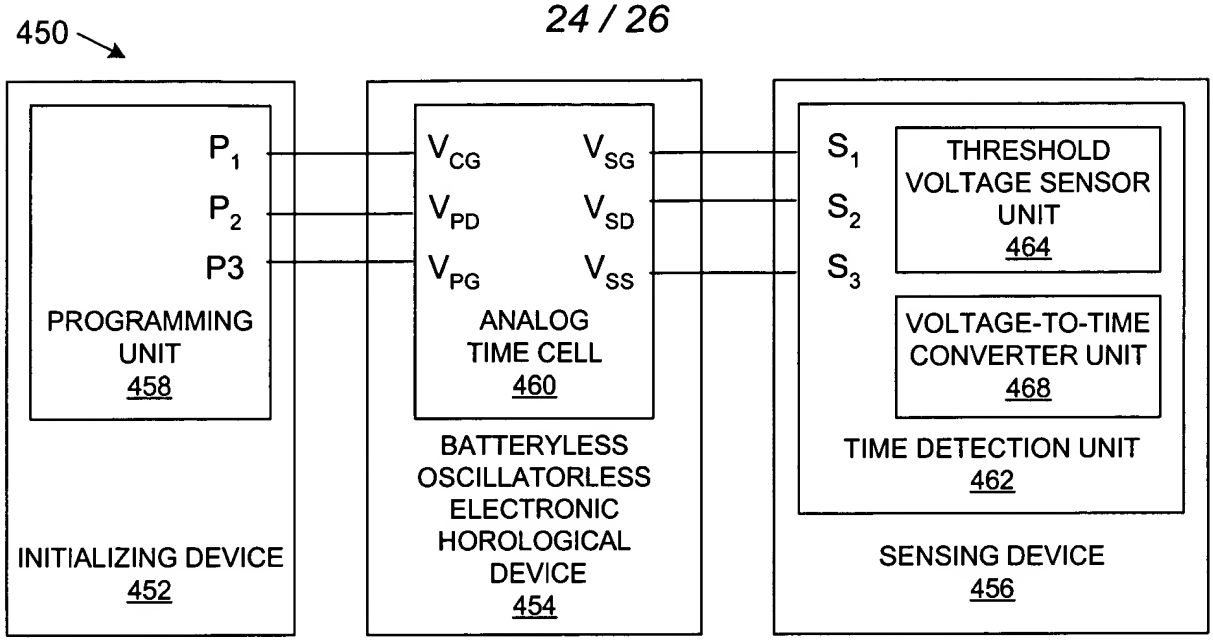


Figure 4K

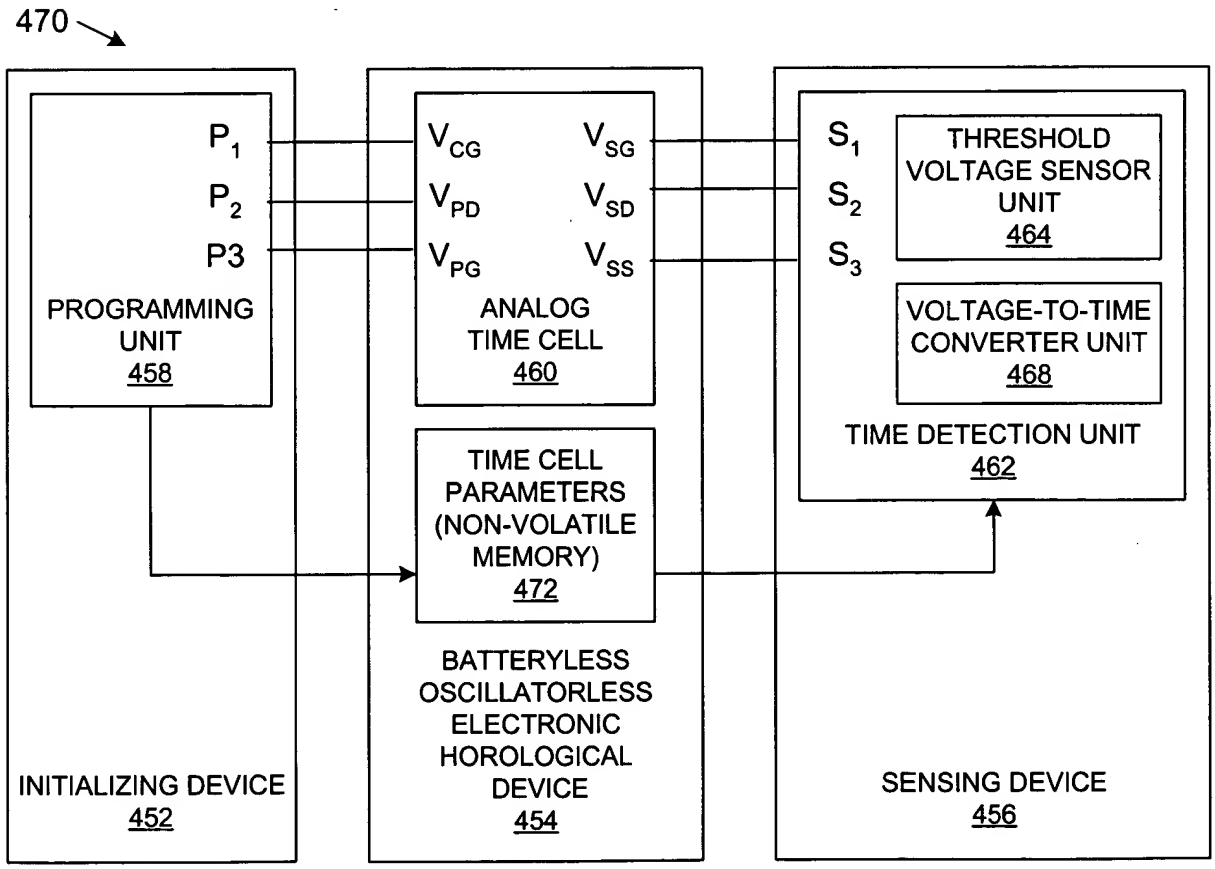


Figure 4L

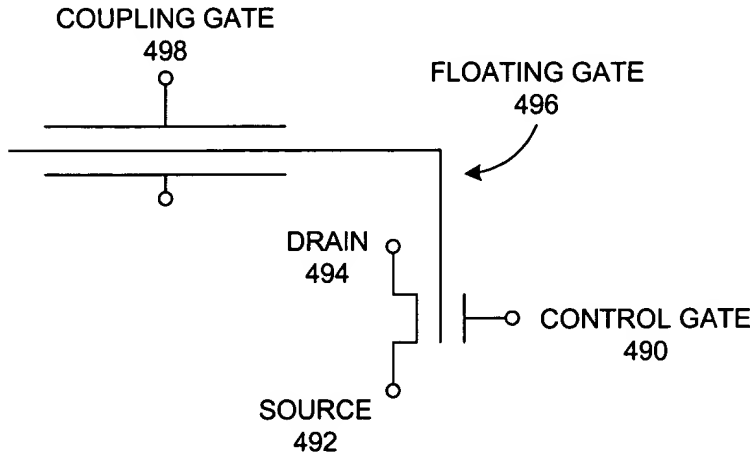


Figure 4M

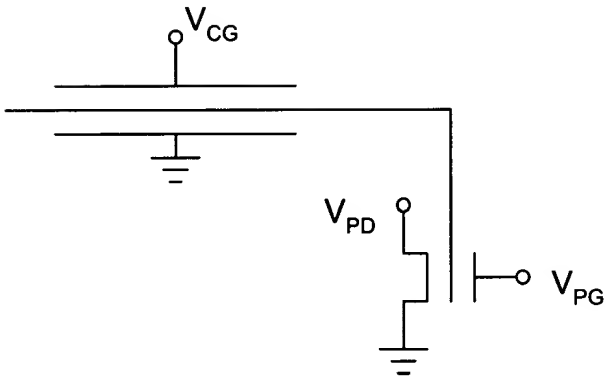


Figure 4N

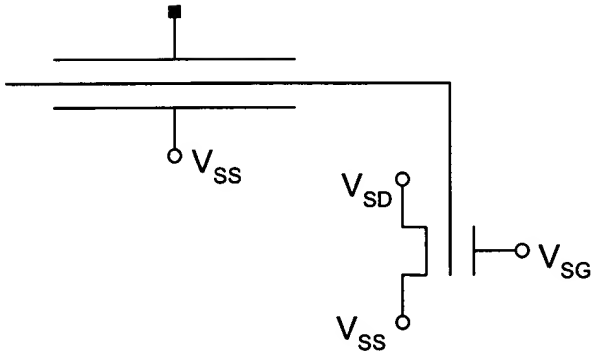


Figure 4O

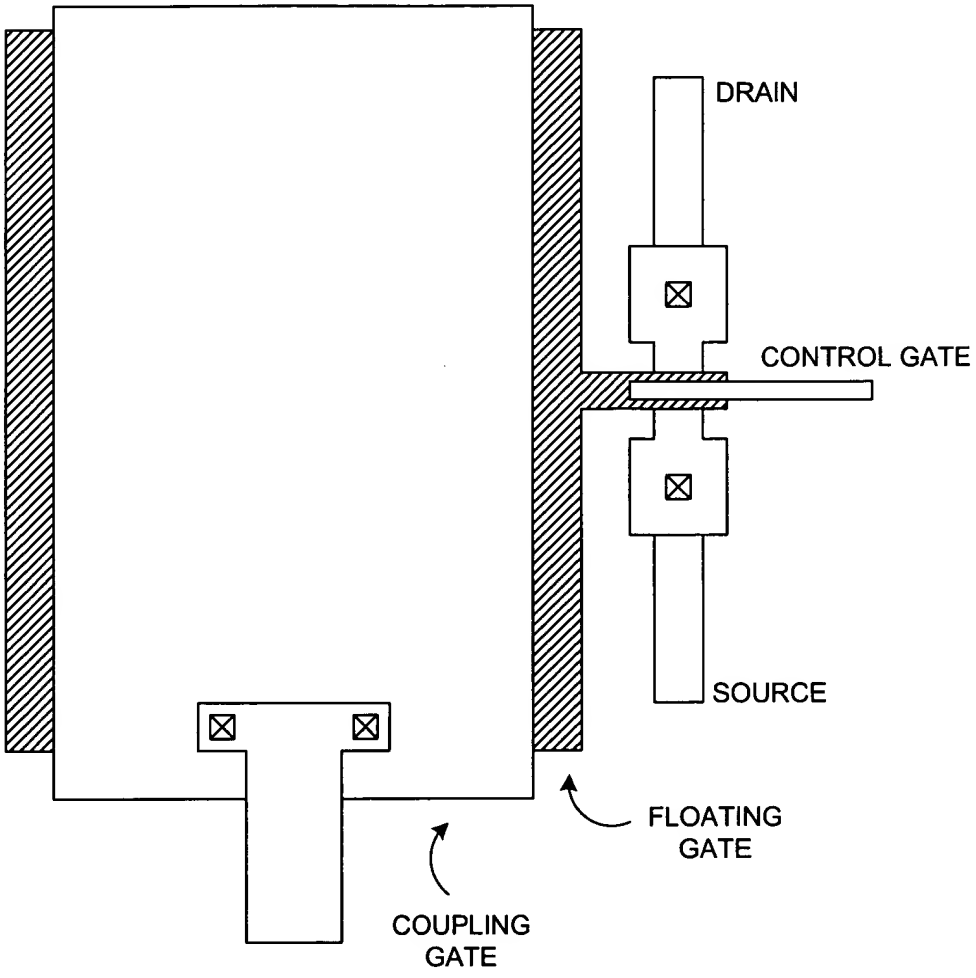


Figure 4P